BLF6G22LS-40BN

Power LDMOS transistor

Rev. 1 — 28 June 2012

Product data sheet

1. Product profile

1.1 General description

40 W LDMOS power transistor for base station applications at frequencies from 2000 MHz to 2200 MHz.

Table 1. Typical performance

RF performance at $T_{\text{case}} = 25 \, ^{\circ}\text{C}$ in a common source class-AB production test circuit.

Mode of operation	f	V _{DS}	P _{L(AV)}	Gp	η_D	ACPR
	(MHz)	(V)	(W)	(dB)	(%)	(dBc)
2-carrier W-CDMA	2110 to 2170	28	2.5	18.5	16	-50 <u>[1]</u>

^[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 8.4 dB at 0.01 % probability on CCDF per carrier; carrier spacing 5 MHz

1.2 Features and benefits

- Typical 2-carrier W-CDMA performance at frequencies of 2110 MHz and 2170 MHz, a supply voltage of 28 V and an I_{Dq} of 345 mA:
 - Average output power = 2.5 W
 - ◆ Power gain = 18.5 dB (typ)
 - ◆ Efficiency = 16 %
 - ◆ ACPR = -50 dBc
- Easy power control
- Integrated ESD protection
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (2000 MHz to 2200 MHz)
- Internally matched for ease of use
- Integrated current sense
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

RF power amplifiers for W-CDMA base stations and multi carrier applications in the 2000 MHz to 2200 MHz frequency range



2. Pinning information

Table 2. Pinning

10010 21	9		
Pin	Description	Simplified outline	Graphic symbol
1	drain	, .	
2	gate		1 4, 5
3	source	[1]	
4, 5	sense drain		3 sym126
6, 7	sense gate		. .

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Packag	ge	
	Name	Description	Version
BLF6G22LS-40BN	-	earless flanged ceramic package; 6 leads	SOT1112B

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
V _{GS(sense)}	sense gate-source voltage		-0.5	+9	V
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	200	°C
T _{case}	case temperature		<u>[1]</u> -	150	°C

^[1] Continuous use at maximum temperature will affect MTTF.

5. Recommended operating conditions

Table 5. Operating conditions

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
T _{case}	case temperature		-40	-	+125	°C

6. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j\text{-case})}$	thermal resistance from junction to case	$T_{case} = 80 ^{\circ}C; P_{L} = 12.5 W (CW)$	1.7	K/W

BLF6G22LS-40BN

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7. Characteristics

Table 7. Characteristics

 $T_i = 25$ °C per section; unless otherwise specified

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.5 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 59 \text{ mA}$	1.4	1.9	2.4	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	1.5	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	8.8	10	-	Α
I _{GSS}	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	150	nA
9 _{fs}	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 2.9 \text{ A}$	-	4.3	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 2.1 \text{ A}$	-	0.25	-	Ω
I_{Dq}	quiescent drain current	main transitor: $V_{DS} = 28 \text{ V}$ sense transitor: $I_{DS} = 7.43\text{mA}$; $V_{DS} = 26.7 \text{ V}$	310	345	380	mA

8. Test information

Table 8. Application information

Mode of operation: 2-carrier W-CDMA; PAR 8.4 dB at 0.01 % probability on CCDF; 3GPP test model 1; 1 to 64 DPCH; f_1 = 2112.5 MHz; f_2 = 2117.5 MHz; f_3 = 2162.5 MHz; f_4 = 2167.5 MHz; RF performance at V_{DS} = 28 V; I_{Dq} = 345 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit

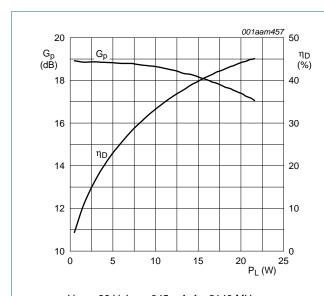
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
G_p	power gain	$P_{L(AV)} = 2.5 W$	17.5	18.5	19.9	dB
η_{D}	drain efficiency	$P_{L(AV)} = 2.5 \text{ W}$	13	16	-	%
ACPR	adjacent channel power ratio	$P_{L(AV)} = 2.5 W$	–57	-50	-45	dBc
PARO	output peak-to-average ratio	$P_{L(AV)} = 20 \text{ W}$	3.6	4.0	4.8	dB
RLin	input return loss	$P_{L(AV)} = 20 \text{ W}$	-	-16	-9	dB

^[1] Mode of operation: 1-carrier W-CDMA; PAR 7.2 dB at 0.01 % probability on CCDF; f = 2167.5 MHz.

8.1 Ruggedness in class-AB operation

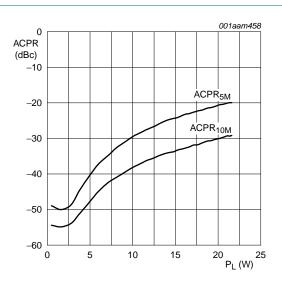
The BLF6G22LS-40BN is capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: V_{DS} = 28 V; I_{Dq} = 345 mA; P_{L} = 40 W (CW); f = 2140 MHz.

8.2 2-Carrier W-CDMA with 5 MHz carrier spacing



 $V_{DS} = 28 \text{ V}; I_{Dq} = 345 \text{ mA}; f = 2140 \text{ MHz}.$

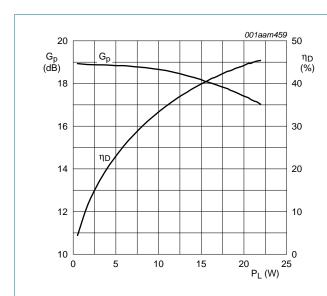
Fig 1. Power gain and drain efficiency as function of load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 345 \text{ mA}; f = 2140 \text{ MHz}.$

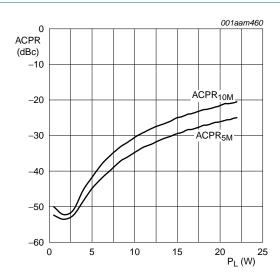
Fig 2. Adjacent channel power ratio at 5 MHz and at 10 MHz as function of load power; typical values

8.3 2-Carrier W-CDMA with 10 MHz carrier spacing



 V_{DS} = 28 V; I_{Dq} = 345 mA; f = 2140 MHz.

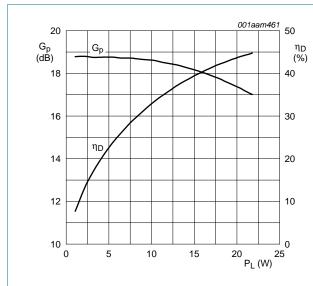
Fig 3. Power gain and drain efficiency as function of load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 345 \text{ mA}; f = 2140 \text{ MHz}.$

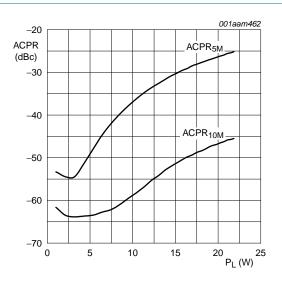
Fig 4. Adjacent channel power ratio at 5 MHz and at 10 MHz as function of load power; typical values

8.4 1-Carrier W-CDMA



 $V_{DS} = 28 \text{ V}; I_{Dq} = 345 \text{ mA}; f = 2140 \text{ MHz}.$

Fig 5. Power gain and drain efficiency as function of load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 345 \text{ mA}; f = 2140 \text{ MHz}.$

Fig 6. Adjacent channel power ratio at 5 MHz and at 10 MHz as function of load power; typical values

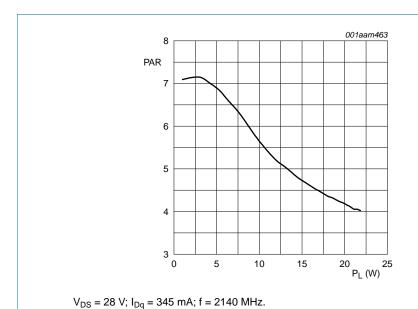
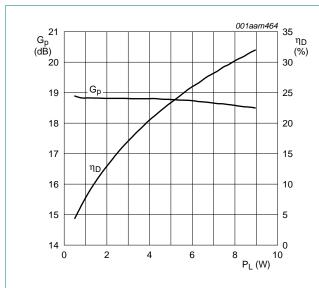


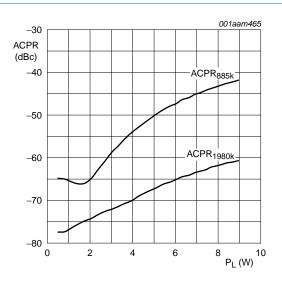
Fig 7. Peak-to-average power ratio as a function of load power; typical values

8.5 1-Carrier IS-95



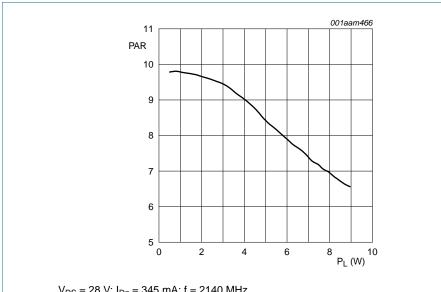
 $V_{DS} = 28 \text{ V}; I_{Dq} = 345 \text{ mA}; f = 2140 \text{ MHz}.$

Power gain and drain efficiency as function of Fig 8. load power; typical values



 $V_{DS} = 28 \text{ V}; I_{Dq} = 345 \text{ mA}; f = 2140 \text{ MHz}.$

Adjacent channel power ratio at 885 kHz and at Fig 9. 1980 kHz as function of load power; typical values



 V_{DS} = 28 V; I_{Dq} = 345 mA; f = 2140 MHz.

Fig 10. Peak-to-average power ratio as a function of load power; typical values

8.6 1-Tone CW

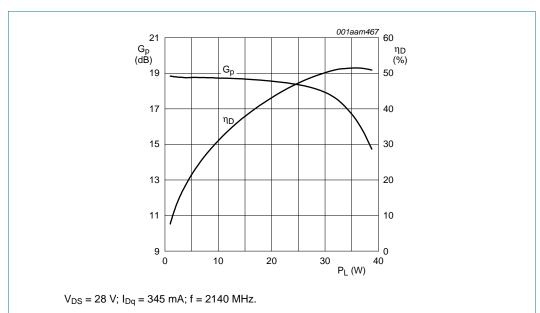


Fig 11. Power gain and drain efficiency as function of load power; typical values

8.7 Test circuit

Table 9. List of components For test circuit see Figure 12.

Component	Description	Value	Remarks
C3, C8, C9	multilayer ceramic chip capacitor	33 pF	[1]
C5	multilayer ceramic chip capacitor	1.0 pF	[1]
C6	multilayer ceramic chip capacitor	100 nF	[2]
C10	multilayer ceramic chip capacitor	33 pF	[3]
C11, C15	multilayer ceramic chip capacitor	47 pF	[3]
C12	multilayer ceramic chip capacitor	10 μF	[2]
C13	electrolytic capacitor	470 μF; 63 V	
R1	SMD resistor	10 Ω	Philips 0603
R2	SMD resistor	820 Ω	Philips 0603
R3	SMD resistor	1.8 kΩ	Philips 0603

^[1] American Technical Ceramics type 800B or capacitor of same quality.

^[2] TDK or capacitor of same quality.

^[3] American Technical Ceramics type 100A or capacitor of same quality.

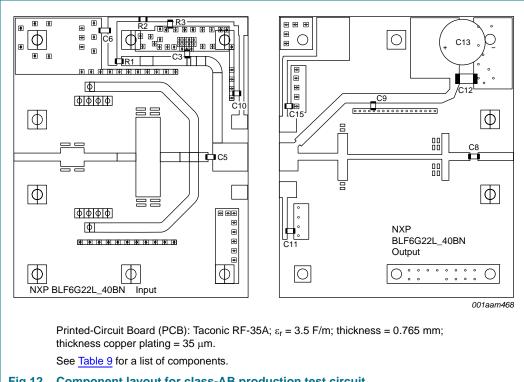


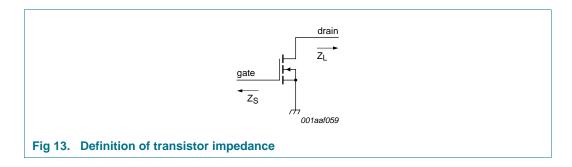
Fig 12. Component layout for class-AB production test circuit

8.8 Impedance information

Table 10. Typical impedance

Typical values valid for both section in parallel unless otherwise specified.

• •	•	•
f	Z _S	Z _L
(MHz)	(Ω)	(Ω)
2050	3.3 – j12.2	13 – j11.2
2140	4.5 – j12.8	12.2 – j6.9
2230	10 – j15.3	13.3 – j5.5



9. Package outline

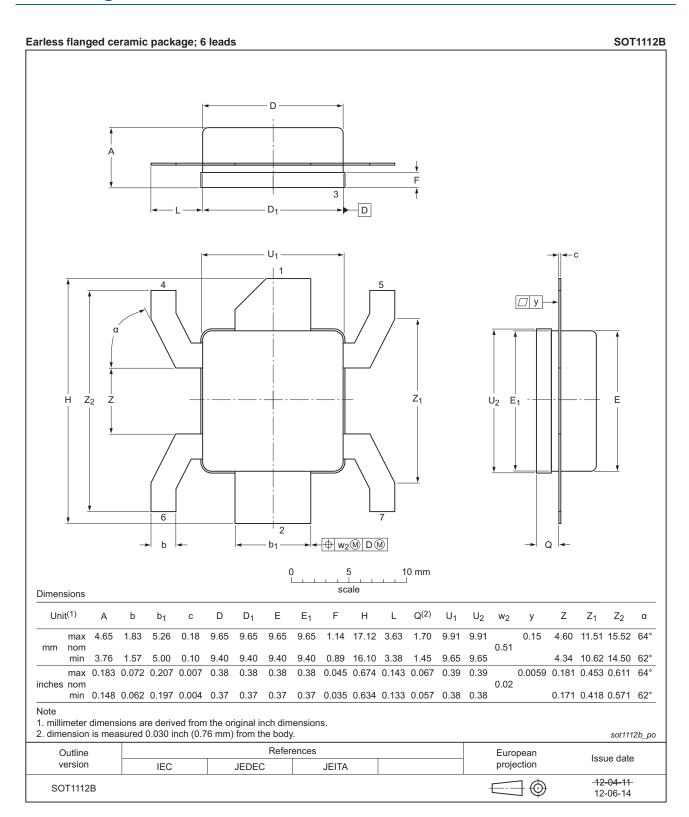


Fig 14. Package outline SOT1112B

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10. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

11. Abbreviations

Table 11. Abbreviations

Acronym	Description
3GPP	3rd Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
CW	Continuous Waveform
DPCH	Dedicated Physical CHannel
ESD	ElectroStatic Discharge
IS-95	Interim Standard 95
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
MTTF	Mean Time To Failure
PAR	Peak-to-Average Ratio
SMD	Surface Mounted Device
VSWR	Voltage Standing-Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

12. Revision history

Table 12. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BLF6G22LS-40BN v.1	20120628	Product data sheet	-	-

13. Legal information

13.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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